

**Search Notes**

Application/Control No.

10/647,540

Examiner

ALEX LIEW

Applicant(s)/Patent under  
Reexamination

NAPHADE ET AL.

Art Unit

2624

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
382/181-231 limited to text search	8/27/2008	AL